

FORM PTO-1449, Adapted

**LIST OF INFORMATION DISCLOSED BY APPLICANT**

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ATTY. DOCKET NO.  
**12610-0190**SERIAL NO.  
**08/588,484**FILING DATE  
**January 18, 1996**APPLICANT(S)  
**Thomas G. Thundat, et al.**GROUP  
**2878**

SEP 03 1999

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>PH</i>	AA	3,415,712	12/10/68	R. E. Barker, Jr.			10/31/63
	AB	4,236,893	12/02/80	Rice			04/09/79
	AC	4,242,096	12/30/80	Oliveira et al.			11/14/77
	AD	4,427,881	01/24/84	Ruell			03/09/81
	AE	4,596,697	06/24/86	Ballato			09/04/84
	AF	4,637,987	01/20/87	Minten et al.			05/07/84
	AG	4,735,906	04/05/88	Bastiaans			11/28/84
	AH	4,762,426	08/09/88	Foss			12/19/86
	AI	4,847,193	07/11/89	Richards, et al.			06/18/87
	AJ	4,905,701	03/06/90	Cornelius			06/15/88
<i>PH</i>	AK	4,906,840	03/06/90	Zdeblick et al.			01/27/88

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	TRANSLATION YES NO.
	AL					
	AM					
	AN					
	AO					

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

<i>PH</i>	AP	"Microfabrication of Cantilever Styli for the Atomic Force Microscope" by T.R. Albrecht, S. Akamine, T.E. Carver and C. F. Quate, Journal of Vacuum Science & Technology A, Vol. 8, No. 4, Jul./Aug. 1990, pp. 3386-3396.
	AR	"A Mechanical Nanosensor in the Gigahertz Range: Where Mechanics Meets Electronics", by Vu Thien Binh, N. Garcia, A. L. Levanuyk, Surface Sciences, Vol. 301, Nos. 1-3, Jan. 10, 1994, pp. 1,224-1,228.
	AS	"A Nondestructive Method for Determining the Spring Constant of Cantilevers for Scanning Force Microscopy" by J. P. Cleveland and S. Manne, D. Bocek, P. K. Hansma, Review of Scientific Instruments, Vol. 64, No. 2, Feb. 1993, pp. 403-405.
<i>PH</i>	AT	"Adhesion Forces Between Individual Ligand-Receptor Pairs" by Ernst-Ludwig Florin, Vincent T. Moy, Hermann E. Gaub, Science, Vol. 264, 15 April 1994, pp. 415-417.

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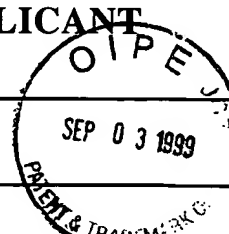
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<i>RA</i>	AU	4,999,284	03/12/91	Ward et al.	T	T	04/06/88
	AV	5,001,053	03/19/91	Takahashi et al.			09/12/88
	AW	5,130,257	07/14/92	Baer et al..			09/29/88
	AX	5,135,852	08/04/92	Ebersole et al.			07/25/89
	AY	5,156,972	10/20/92	Issachar			09/05/90
	AZ	5,221,415	06/22/93	Albrecht et al.			11/26/90
	BA	5,283,087	02/01/94	Baer et al.			11/15/91
	BB	5,306,644	04/26/94	Myerholtz et al.			04/01/93
	BC	5,323,636	06/28/94	McGowan et al.			06/11/93
	BD	5,179,028	01/12/93	Vali et al.			04/20/90
<i>RA</i>	BE	5,339,675	08/23/94	DiLeo et al..			10/08/92

**FOREIGN PATENT DOCUMENTS**

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					YES	NO.
	BF					
	BG					
	BH					
	BI					

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

<i>RA</i>	BJ	"Measuring Intermolecular Binding Forces with the Atomic-Force Microscope: The Magnetic Jump Method" by Jan H. Hoh, Paul E. Hillner and Paul K. Hansma, Fifty-Second Annual Meeting Microscopy Society of America, Twenty-Ninth Annual Meeting Microbeam Analysis Society, 31 July-5 August 1994, pp 1054-1055
<i>RA</i>	BK	"Quantized Adhesion Detected with the Atomic Force Microscope" by Jan H. Hoh, Jason P. Cleveland, Craig B. Prater, Jean-Paul Revel and Paul K. Hansma, Journal of the American Chemical Society, Vol. 114, No. 12, June 3, 1992, pp 4917-4918.
<i>RA</i>	BL	"Sensing Discrete Streptavidin-Biotin Interactions with Atomic Force Microscopy" by Gil U. Lee, David A. Kidwell, and Richard J. Colton, Langmuir, Vol. 10, No. 2, Feb. 1994, pp. 354-357.
	BM	

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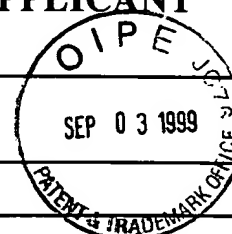
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<i>RAH</i>	BN	5,363,697	11/15/94	Nakagawa			04/29/92
	BO	5,372,930	12/13/94	Colton et al.			09/16/92
	BP	5,411,709	05/02/95	Furuki et al.			03/24/92
	BR	5,445,970	08/29/95	Rohr			12/01/94
	BS	5,445,971	08/29/95	Rohr			12/01/94
	BT	5,477,716	12/26/95	Snow			07/27/94
	BU	5,482,678	01/09/96	Sittler.			11/10/94
	BV	5,494,639	02/27/96	Grzegorzewski.			10/13/94
	BW	5,501,986	03/26/96	Ward et al.			07/28/94
	BX	5,550,516	08/27/96	Burns et al.			12/16/94
<i>RAH</i>	BY	5,552,274	09/03/96	Oyama et al.			09/07/93

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	BZ				
	CA				
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	CC				

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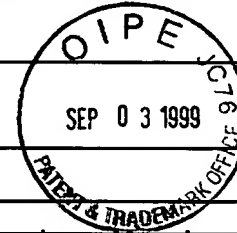
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<i>AM</i>	CH	5,595,908	01/21/97	Fawcett et al.			08/11/89
	CI	5,620,854	04/15/97	Holzrichter et al.			03/13/95
	CJ	5,658,732	08/19/97	Ebersole et al.			03/01/95
	CK	5,705,399	01/06/98	Larue			05/20/94
	CL	5,719,324	02/17/98	Thundat et al.			06/16/95
	CM	5,763,768	06/09/98	Henderson et al.			03/17/97
	CN	5,844,238	12/01/98	Sauer et al..			03/27/96
	CO	5,866,328	02/02/99	Bensimon et al.			04/06/94
<i>AM</i>	CP	Re. 35,544	07/01/97	Snow			07/27/94
	CR						
	CS						

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	CT					
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	CZ	
	DA	
	DB	

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